

MSE-628

CCMX Advanced Course - Advanced X-ray Diffraction Methods for Coatings: strain, defects and deformation analysis of thin films

Dommann Alex, Neels Antonia

Cursus	Sem.	Type
Materials Science and Engineering		Opt.

Language of teaching	English
Credits	1
Session	
Exam	Written
Workload	30h
Hours	18
Lecture	13
Practical work	5
Number of positions	16

Frequency

Every 2 years

Remark

Next time: November 22-24, 2023

Summary

After introducing thin film and HR-XRD characterisation methods, theory and limitations are discussed, including examples and how the film structure influences its characteristics. Protocols are presented for establishing reproducible and reliable measurements, and for interpreting their results.

Content

Please find information on the link below : <https://www.epfl.ch/research/domains/ccmx/courses-and-events/axrd23/>

Resources

Websites

- <https://www.epfl.ch/research/domains/ccmx/courses-and-events/axrd23/>